Search Notes			

Application/Control No.	Applicant(s)/Patent under Reexamination
10/821,527	YANG ET AL.
Examiner	Art Unit
Hieu Nguyen	2817

SEARCHED				
Class	Subclass	Date	Examiner	
330	10	8/26/2005	НИ	
330	207A	8/25/2005	HN	
330	251	8/25/2005	HN	
		<u>-</u>		
		=:		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner
	<u> </u>		

SEARCH NO (INCLUDING SEARCH)
	DATE	EXMR
MOTTOLA STEVEN J	8/30/2005	HN
NGUYEN KHANH V	8/29/2005	HN
	·	